

X-RAY FLUORESCENCE

MANUFACTURER : Fisher Technology

MODEL : Fischerscope X-RAY XDV- μ

Analysis

- Spot size of X-ray beam is 50 microns of diameter
- Adjustable primary energy from 50 keV – 40 keV – 30 keV
- Primary filter choices are: None, Al 1000 microns, Al 500 microns or Ni 10 microns
- Camera system with high magnification for alignment
- Auto-alignment feature
- Maximum sample size of 25 cm x 25 cm x 10 cm
- Thickness measurement uncertainty smaller than 1 nm possible
- Concentration measurement precision of 0.1%

Application

- Material analysis (standard free) or thickness measurement (with calibration standard)

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Example

μ XRF is a non-destructive technique which enables to determine the materials composition inside a sample.

The table below shows present elements and their composition.

Block No:32	Sn (%)	Ag (%)	Cu (%)	Pb (%)
Mean value	94.87	4.340	0.766	0.020
Standard Dev.	0.331	0.268	0.082	0.007
C.O.V.[%]	0.35	6.17	10.67	32.41
No of Readings	5	5	5	5
Order No.	Qualification conc Sn-Ag-Cu-Pb			